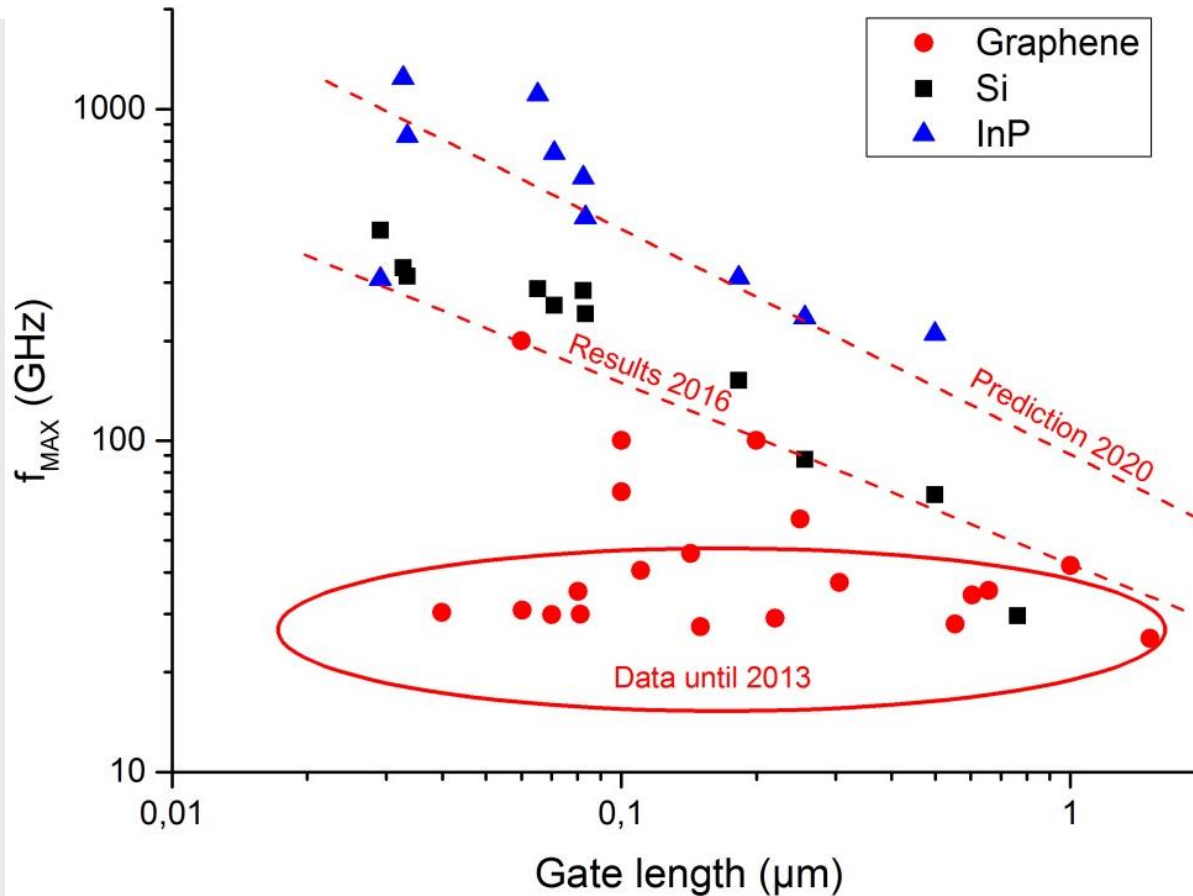




Integrated Circuits for RF Communication with Graphene based Devices

Daniel Neumaier

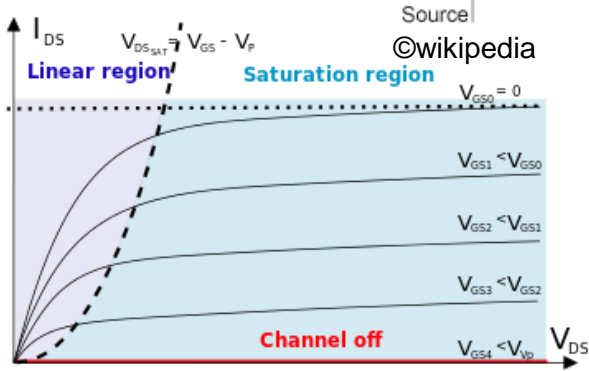
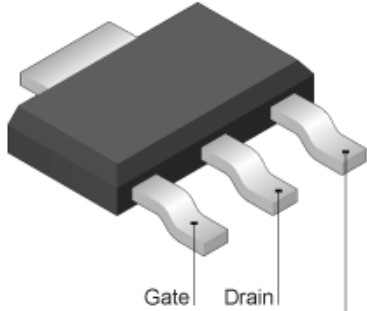
Advanced Microelectronic Center Aachen, AMO GmbH



- f_{MAX} is still improving due to optimized GFET fabrication.
- Highest values are already competitive to Si CMOS.
- It is expected that InP can be matched until 2020.

High Frequency Electrical Components

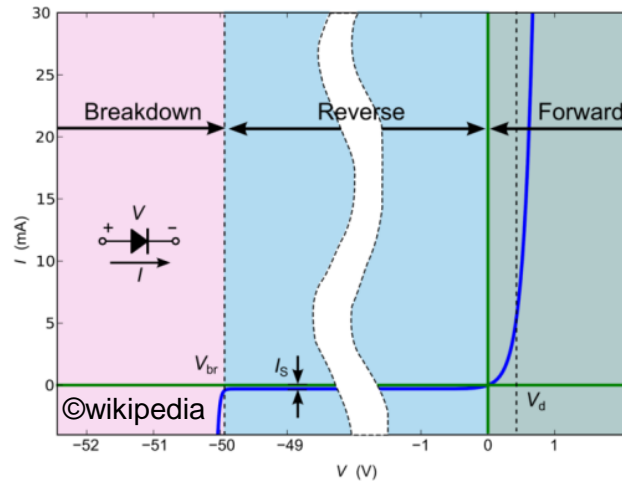
Transistor



- Amplification
- MOS integrated circuits
- CMOS circuits
- Analog switches
- Power detection

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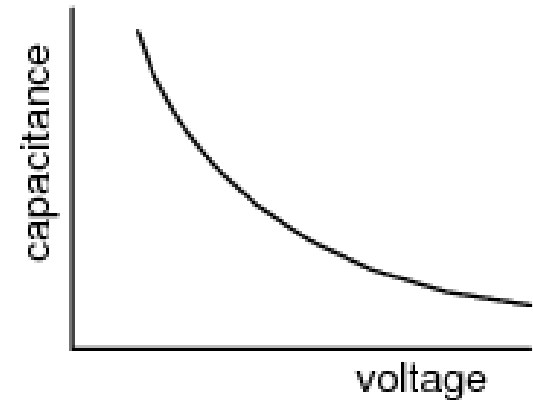
Diode



- Radio demodulation
- Power conversion
- Over-voltage protection
- Logic gates

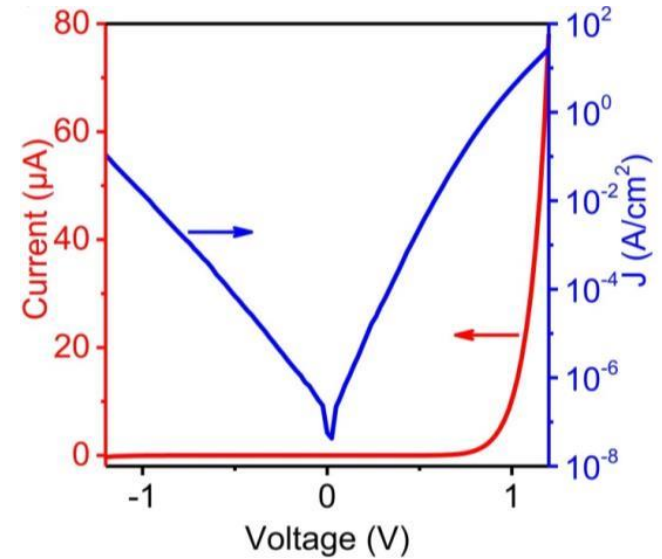
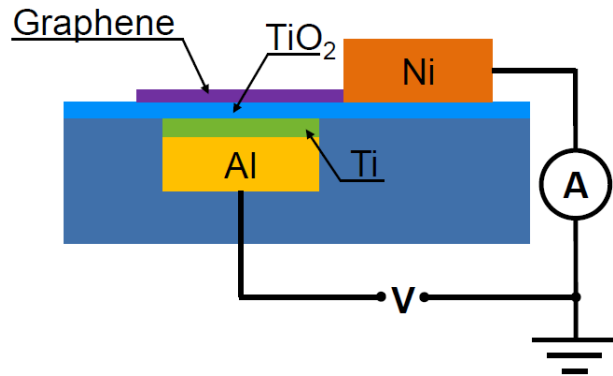
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Varactor

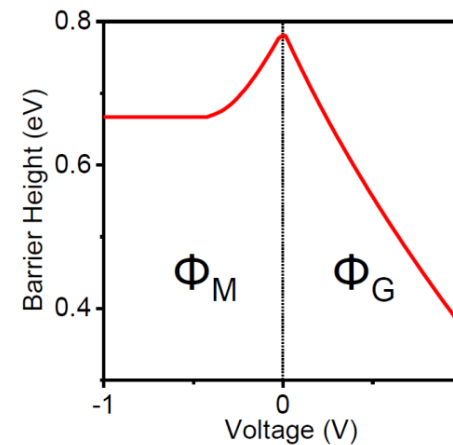
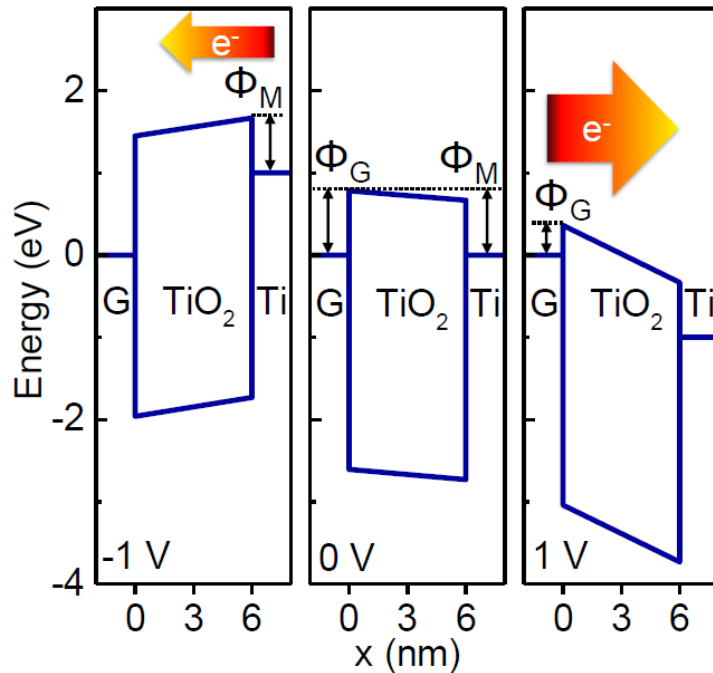


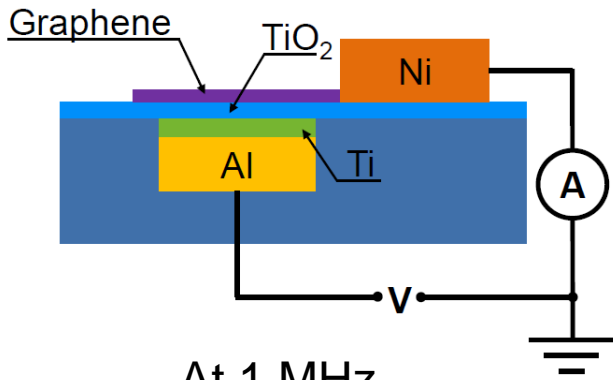
- Voltage-controlled oscillators
- Parametric amplifiers
- Frequency multipliers

.....



Bias induced barrier lowering



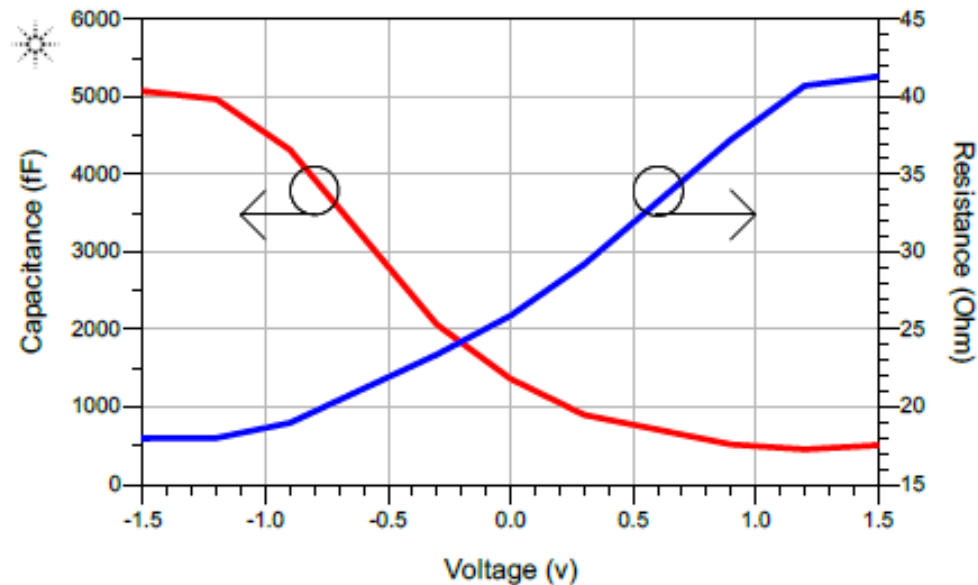
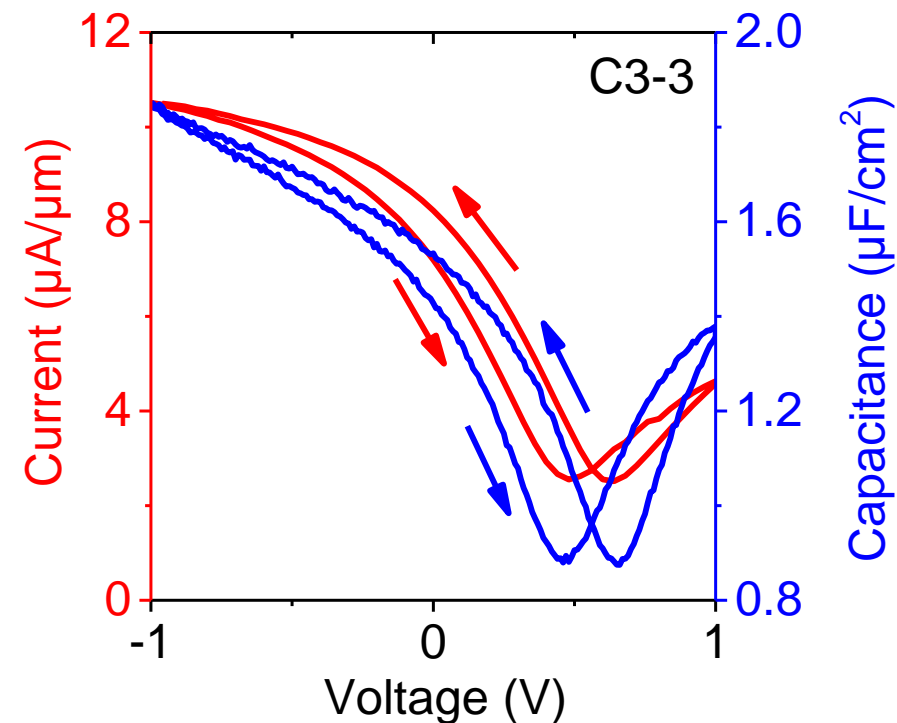


At 1 MHz

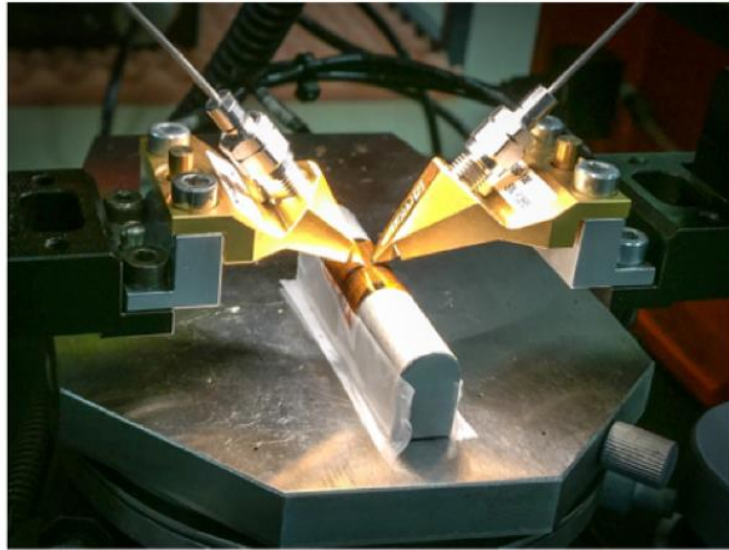
Varactor behaviour of MIG Diode:

- Quantum Capacitance of Graphene

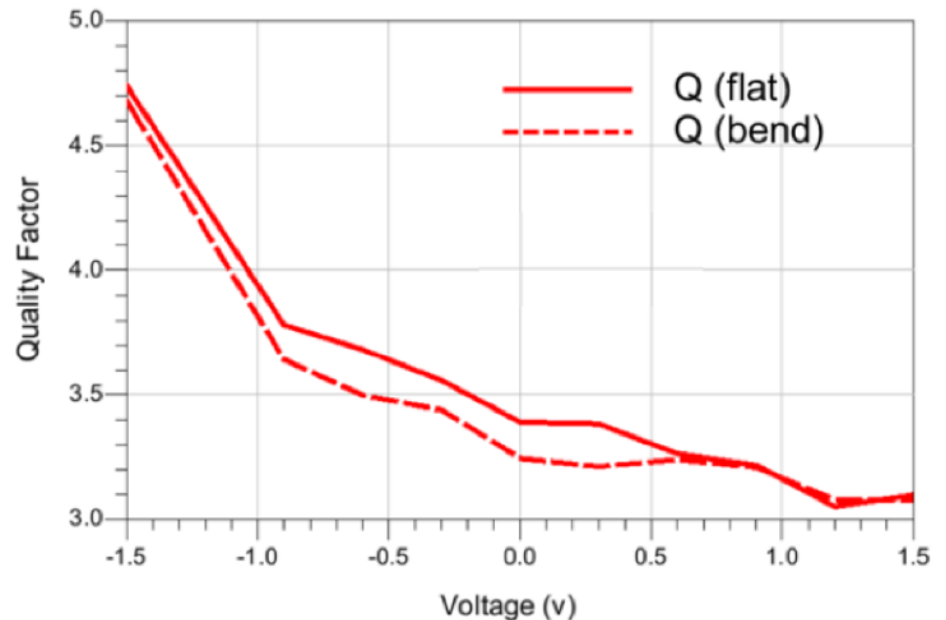
At 20 GHz from S parameters



RF measurements of diodes

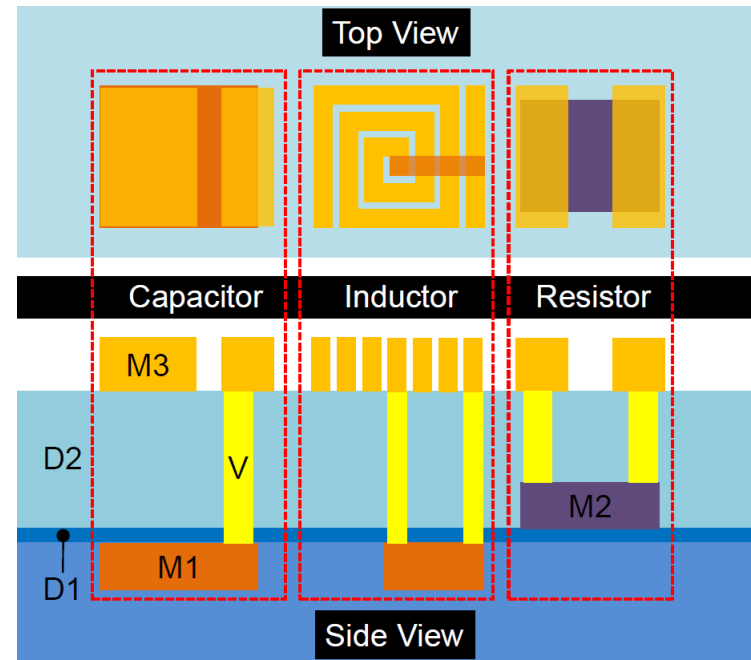
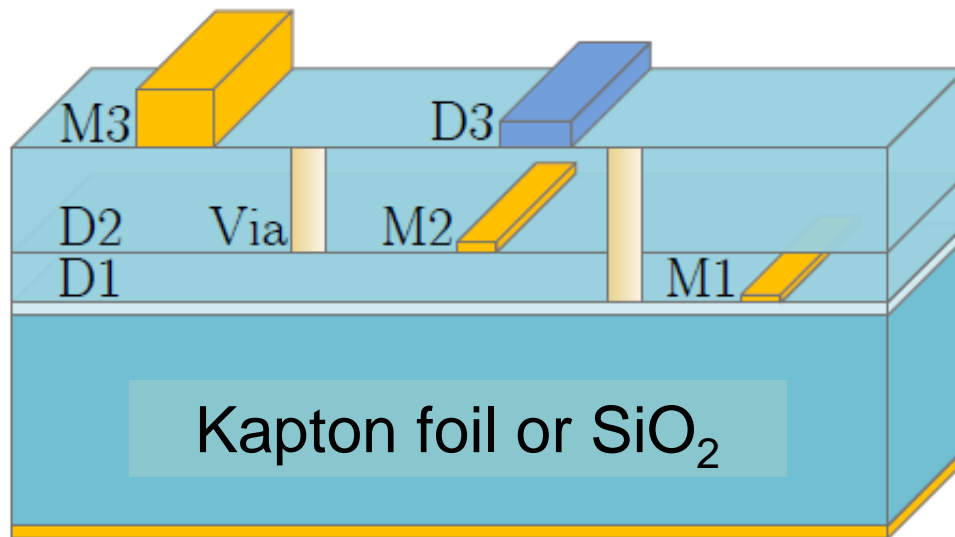


Measured Q-factor at 60 GHz



- Operation at 60 GHz demonstrated (Q=4). Cut-off frequency >100 GHz.
- Same performance in the bended state.
- With design optimization THz operation feasible.

MMIC Process on Any Substrate



3 Dielectric layers:

- D1: 5 nm TiO₂ (diodes, varactors) or 5-10 nm Al₂O₃ (transistors)
- D2: 90nm Al₂O₃ (encapsulation, capacitors)
- D3 500 nm SU8 (inductors)

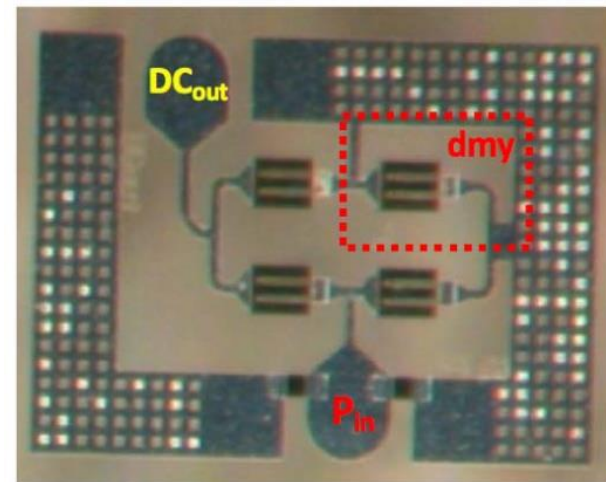
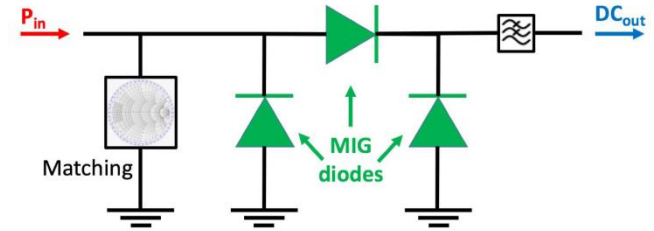
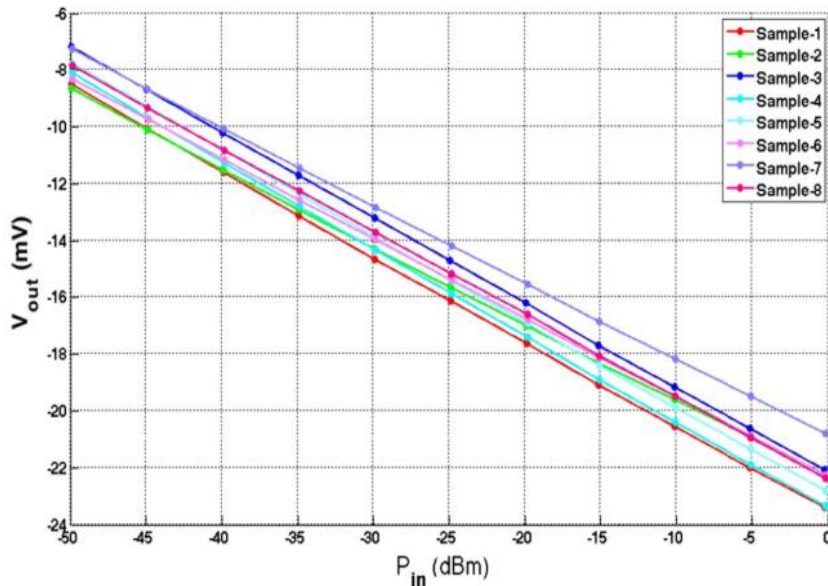
4 Metal layers:

- M1: 100nm Al (gate electrode, passives)
- M2a: 20 nm Nickel (graphene contacts)
- M2b: 110 nm TiN (resistors)
- M3: 2 μ Al (passives, interconnects)

Graphene is between D1 and M2, and can be used in diodes, varactors or/and transistors.

Implemented using:

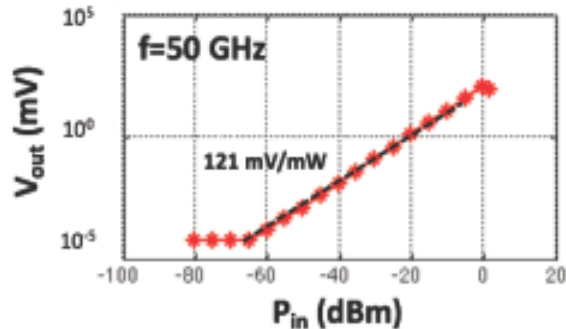
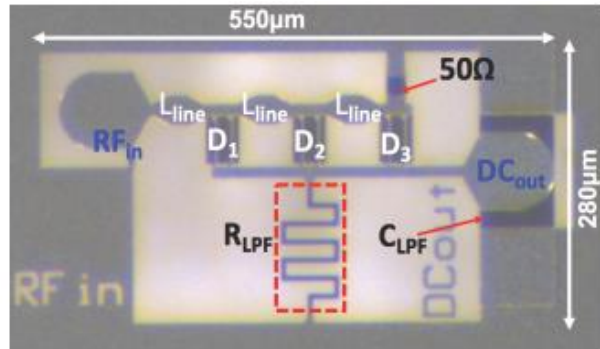
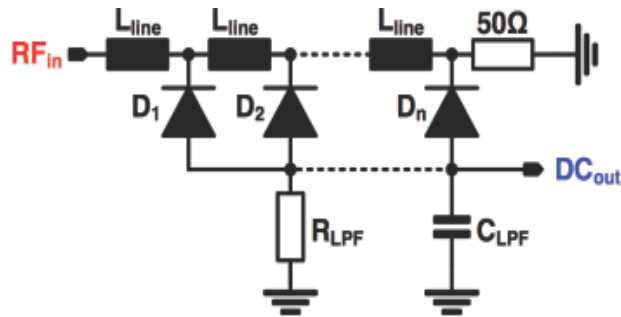
- GFET: up to 110 GHz
- MIG-diode: up to 70 GHz



Comparison with competing technologies

| Ref. | Tech./Sub. | Scheme | DR (dB) | P_{min}/TSS (dBm) | Area (mm ²) | Responsivity (V/W) | Frequency (GHz) |
|-----------------|--------------------|----------------|---------|---------------------|-------------------------|--------------------|-----------------|
| [Saeed:2017cra] | 500 μ m quartz | Linear-in-dB | 50 | -50 | 0.15 | 15 | 60 |
| [Wei:2017do] | 65nm CMOS | Distributed CG | 20 | -23 | 0.45 | 68 | 110 |
| [Hrobak:2013bq] | GaAs Schottky | Single diode | 25 | -50 | 0.635 | 1000 | 110 |

Distributed feedback power detector



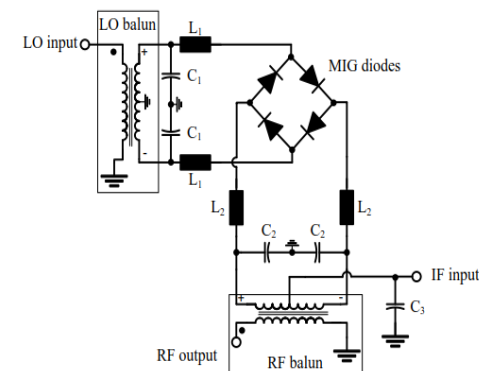
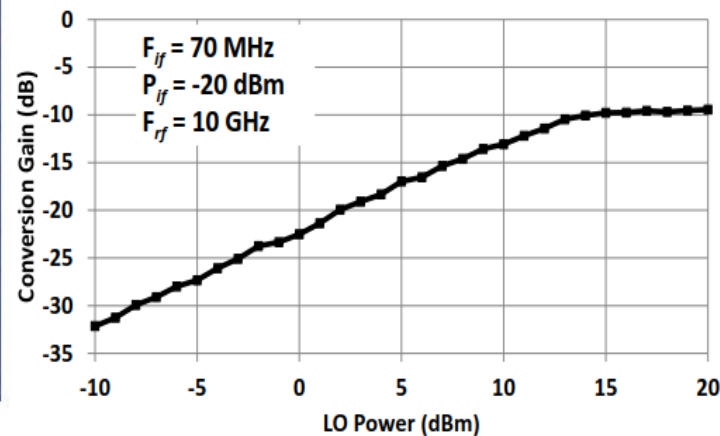
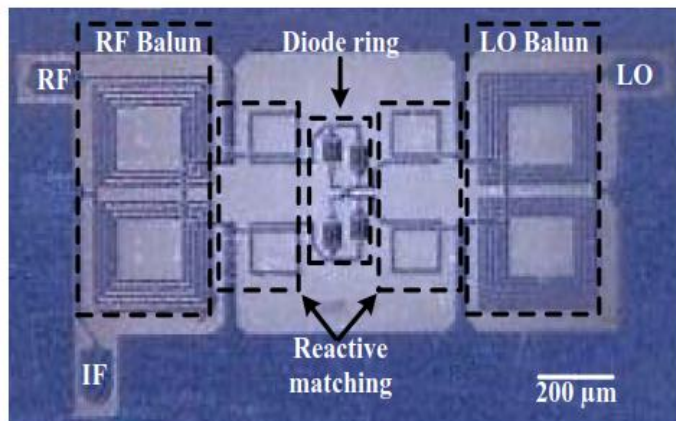
| Ref. | Tech. | P_{DC} (mW) | DR (dB) | TSS (dBm) | Freq. (GHz) |
|------------------|-------------------------|---------------|---------|-----------|-------------|
| [2] | GFET | 0 | 40 | -60 | 3 |
| [8] | 65nm-CMOS | 0.029 | 21 | -36 | 0.01-110 |
| [9] | 65nm-CMOS | 0 | 20 | -40 | 0.01-110 |
| [10] | GaAs Schottky | 0 | 25 | -57 | 60-110 |
| [13] | 0.25 μm SiGe | 7.2 | 52 | -45 | 7-20 |
| This work | Custom MMIC | 0 | >60 | -65 | DC-70 |

Diode based power detector:

- Excellent linearity.
- High sensitivity.

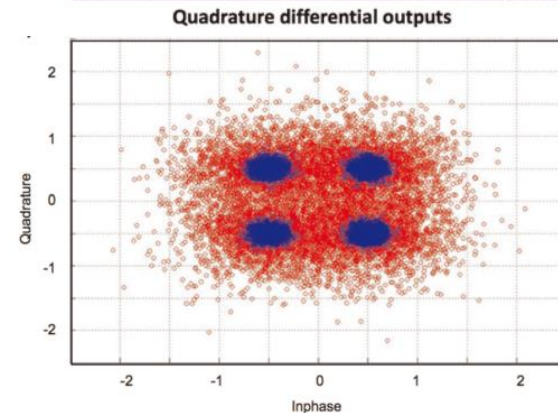
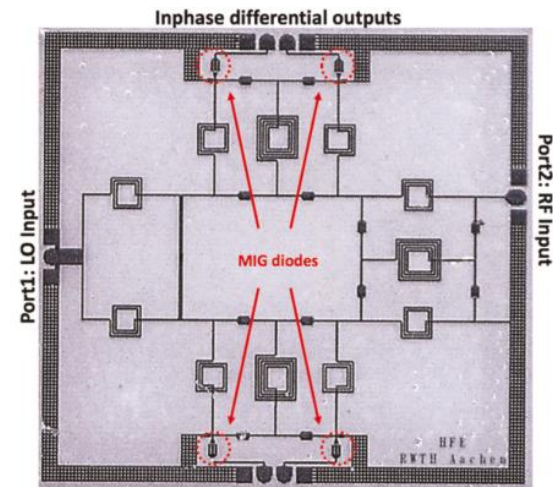
➤ Outperforms SOTA!

6-12 GHz Double balanced upconversion mixer (MIG-diode on glass MMIC)



| Ref. | Substrate | Device | Scheme | RF frequency | Conversion gain |
|------------------|--------------|-----------------------|--|-----------------|-----------------|
| [2] | Silicon-CMOS | GFET | Double-balanced, partially integrated, resistive mixer | 3.5 GHz | -33 dB |
| [3] | Silicon | GFET | Single-device, hybrid, resistive mixer | 4 GHz | -45 dB |
| [4] | SiC | GFET | Single-device, integrated, resistive mixer | 88-100 GHz | -18 dB |
| [8] | GaAs | Schottky diode | Double-balanced, fully integrated, diode mixer | 5-12 GHz | -9 dB |
| This work | Glass | Graphene-diode | Double-balanced, fully integrated, diode mixer | 6-12 GHz | -10 dB |

- State-of-the-art graphene receiver:
 - Six-port receiver frontend
 - MIG-diodes based power detectors
 - Characterized at:
 - $P_{in} = -15$ dBm
 - $f_{in} = 2.45$ GHz
 - 20 Mbps, QPSK

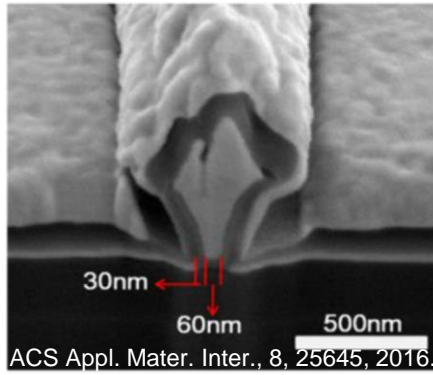


- Graphene receivers

| Ref. | Tech./Sub. | Scheme | Modulation | f_{RF} (GHz) | P_{LO} (dBm) | P_{DC} (mW) | Conversion gain (dB) |
|------------------|---------------------|----------------------|------------|----------------|----------------|---------------|----------------------|
| [Yogeesh:2015fo] | 125 μ m kapton | 1-GFET | AM | 2.45 | NA | NA | -35 |
| [Han:2014hn] | Si/SiO ₂ | 3-stage /GFET | FM | 4.3 | -2 | 20 | -10 |
| [Saeed:2018cs] | 500 μ m quartz | Sixport/4-MIG diodes | QPSK | 2.45 | 0 | 0 | -7 |

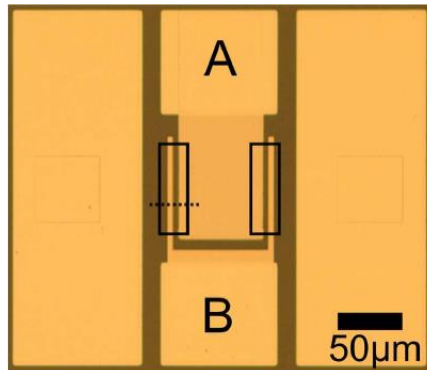
Transistors:

- f_{\max} not yet superior to bulk Si and III/V.
- Limitations are parasitic effects: Gate resistance, contact resist, dielectric, and so on.
- But values are already outstanding for thin film transistors.



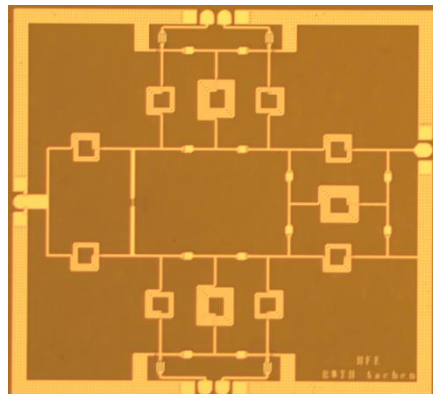
Diodes / Varactors:

- Interesting device concepts enabled by special graphene properties.
- Promising performance, especially suitable for high frequency.



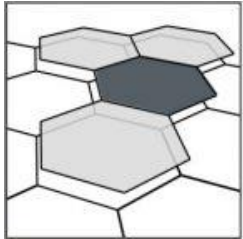
MMIC Process:

- Competitive RF circuits are fabricated based on the in house process and functional circuits based on graphene are demonstrated.



AMO Graphene Team:

Daniel Schall, Sebastian Lukas
Martin Otto, Zhenxing Wang,
Barbara Canto, Burkay Uzlu
Galip Hepgüler, Amir Nekounam,
Daniel Schneider, Santiago Cartamil



**Aachen
Graphene &
2D-Materials
Center**



Main collaborators:

Aixtron, Alcatel-Lucent, Graphenea,
Renato Negra, RWTH Aachen
Christoph Stampfer, RWTH Aachen
Max Lemme, RWTH Aachen
David Jimenez, UA Barcelona
Gianluca Fiori, Uni Pisa
Inessa Bolshakova, Lviv PNU
Frank Koppens, ICFO
Thomas Müller, TU Wien



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